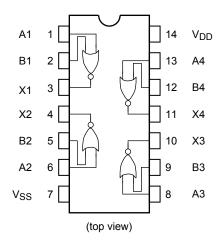
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4001BP,TC4001BF,TC4001BFN,TC4001BFT

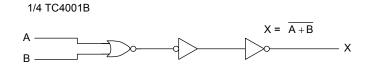
### TC4001B Quad 2 Input NOR Gate

The TC4001B is 2-input positive NOR gate, respectively. Since the outputs of these gates are equipped with the buffers, the input/output transmission characteristics have been improved and the variation of transmission time due to an increase in the load capacity is kept minimum.

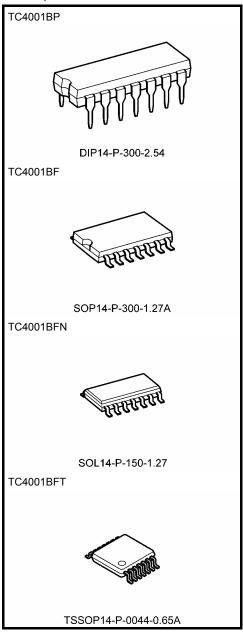
### **Pin Assignment**



### **Logic Diagram**



Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP14-P-300-2.54 : 0.96 g (typ.) SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.) TSSOP14-P-0044-0.65A : 0.06 g (typ.)



### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	V <sub>SS</sub> - 0.5 to V <sub>SS</sub> + 20	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> - 0.5 to V <sub>DD</sub> + 0.5	V
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> - 0.5 to V <sub>DD</sub> + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T <sub>opr</sub>	−40 to 85	°C
Storage temperature range	T <sub>stg</sub>	−65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Operating Ranges (V<sub>SS</sub> = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>	_	0	_	V <sub>DD</sub>	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .



# Static Electrical Characteristics ( $V_{SS} = 0 V$ )

Characteristics			Test Condition		-40°C		25°C			85°C		
		Symbol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
High-leve		V <sub>OH</sub>	I <sub>OUT</sub>   < 1 μA  V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5 10 15	4.95 9.95 14.95	_ _ _	4.95 9.95 14.95	5.00 10.00 15.00	_ 	4.95 9.95 14.95	_ 	٧
Low-leve output vo	-	V <sub>OL</sub>	l <sub>OUT</sub>   < 1 μA V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5 10 15	_ _ _	0.05 0.05 0.05	_ _ _	0.00 0.00 0.00	0.05 0.05 0.05	_ _ _	0.05 0.05 0.05	V
Output h	nigh	lон	V <sub>OH</sub> = 4.6 V V <sub>OH</sub> = 2.5 V V <sub>OH</sub> = 9.5 V V <sub>OH</sub> = 13.5 V V <sub>IN</sub> = V <sub>SS</sub>	5 5 10 15	-0.61 -2.50 -1.50 -4.00	1 1 1 1	-0.51 -2.10 -1.30 -3.40	-1.0 -4.0 -2.2 -9.0	1 1 1 1	-0.42 -1.70 -1.10 -2.80	1 1 1 1	mA
Output lo	ow	l <sub>OL</sub>	$V_{OL} = 0.4 \text{ V}$ $V_{OL} = 0.5 \text{ V}$ $V_{OL} = 1.5 \text{ V}$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15	0.61 1.50 4.00	_ _ _	0.51 1.30 3.40	1.2 3.2 12.0	  -  -	0.42 1.10 2.80	_ _ _	mA
Input hig voltage	gh	V <sub>IH</sub>	V <sub>OUT</sub> = 0.5 V V <sub>OUT</sub> = 1.0 V V <sub>OUT</sub> = 1.5 V  lout  < 1 μA	5 10 15	3.5 7.0 11.0	_ _ _	3.5 7.0 11.0	2.75 5.50 8.25	_ _ _	3.5 7.0 11.0	_ _ _	٧
Input low voltage	v	V <sub>IL</sub>	V <sub>OUT</sub> = 4.5 V V <sub>OUT</sub> = 9.0 V V <sub>OUT</sub> = 13.5 V  l <sub>OUT</sub>   < 1 μA	5 10 15	_ _ _	1.5 3.0 4.0	_ _ _	2.25 4.50 6.75	1.5 3.0 4.0	_ _ _	1.5 3.0 4.0	٧
Input	"H" level	lін	V <sub>IH</sub> = 18 V	18	_	0.1	_	10 <sup>-5</sup>	0.1	_	1.0	μA
current	"L" level	I <sub>IL</sub>	V <sub>IL</sub> = 0 V	18	_	-0.1	_	-10 <sup>-5</sup>	-0.1	_	-1.0	P** .
Quiesce supply c		I <sub>DD</sub>	$V_{IN} = V_{SS}, V_{DD}$ (Note)	5 10 15	1 1 1	0.25 0.50 1.00	_ 	0.001 0.001 0.002	0.25 0.50 1.00	_ _ _	7.5 15.0 30.0	μА

Note: All valid input combinations.

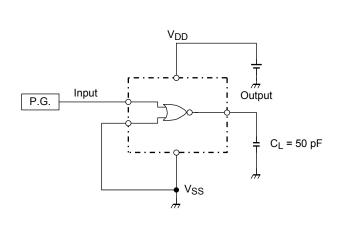


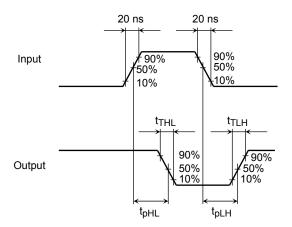
# Dynamic Electrical Characteristics (Ta = 25 $^{\circ}$ C, V<sub>SS</sub> = 0 V, C<sub>L</sub> = 50 pF)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Characteristics	Symbol		V <sub>DD</sub> (V)	IVIII I	τyp.	IVIAX	Offic
			5	_	70	200	
Output transition time	t <sub>TLH</sub>	_	10	_	35	100	ns
			15	1	30	80	
			5	-	70	200	
Output transition time	$t_{THL}$	_	10	_	35	100	ns
			15	1	30	80	
			5	_	65	200	
Propagation delay time	$t_{pLH}$	_	10	_	30	100	ns
			15	1	25	80	
			5	_	65	200	
Propagation delay time	$t_{pHL}$	_	10	_	30	100	ns
			15	-	25	80	
Input capacitance	C <sub>IN</sub>	_		_	5	7.5	pF

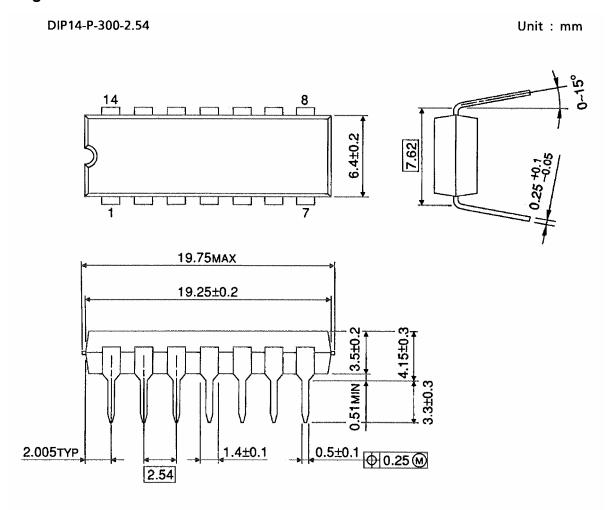
# **Circuit and Waveform for Measurement of Dynamic Characteristics**

Circuit Waveform





# **Package Dimensions**

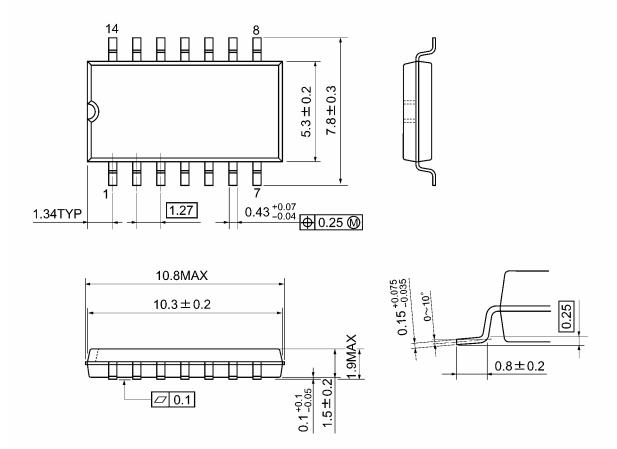


Weight: 0.96 g (typ.)

# **Package Dimensions**

SOP14-P-300-1.27A

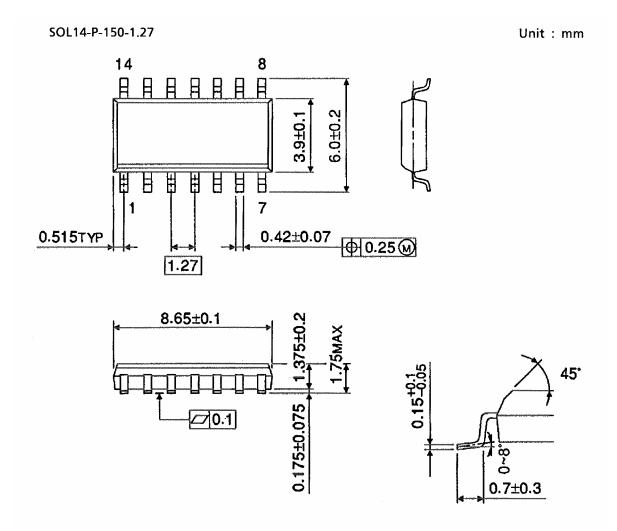
Unit: mm



Weight: 0.18 g (typ.)



# **Package Dimensions (Note)**



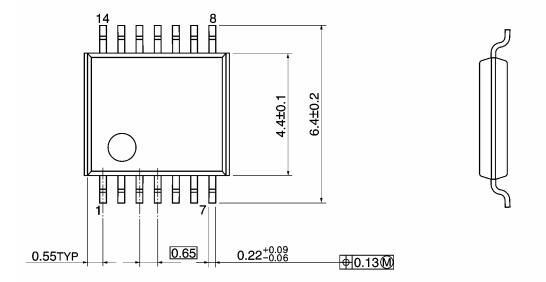
Note: This package is not available in Japan.

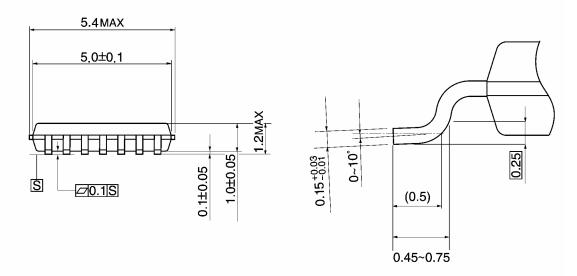
Weight: 0.12 g (typ.)

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# **Package Dimensions**

TSSOP14-P-0044-0.65A Unit: mm





Weight: 0.06 g (typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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